

Report No.: EED32Q80175802 Page 1 of 7

RF Exposure Evaluation Report

Product Remote control

Trade mark Hisense

: ERF6B80HL,ERF6**80*******,*stands Model/Type reference

for 0-9 or A-Z or Blank or "(" or ")"

Serial Number : N/A

Report Number : EED32Q80175802 FCC ID : 2AVIGBR0018

Date of Issue Mar. 27, 2024

47 CFR Part 1.1307 **Test Standards**

47 CFR Part 1.1310 47 CFR Part 2.1091 47 CFR Part 2.1093

KDB 447498 D04 Interim General RF

Exposure Guidance v01

Test result PASS

Aaron Ma

Prepared for:

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Prepared by:

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Report No. : EED32Q80175802

1 Version

Page	2	of	7
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Version No.	Date	Description	
00	Mar. 27, 2024	Original	
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Report No.: EED32Q80175802

Page 3 of 7

Contents

							Page
1 VERSION	l	•••••	••••••	•••••	•••••	•••••	2
	TS						
3.1 CLIEN 3.2 GENEI 3.3 PRODU	L INFORMATION T INFORMATION RAL DESCRIPTION (UCT SPECIFICATION)	DF EUT	THIS STANDARE)			4 4
3.5 DEVIA3.6 ABNO3.7 OTHER	LOCATION ATION FROM STANE RMALITIES FROM S R INFORMATION RE	ARDSTANDARD COND	ITIONSE CUSTOMER				5 5
4.1 RF Ex 4.1.1 L 4.1.2	RPOSURE COMPLIAN Limits Test Procedure EUT RF Exposure	NCE REQUIREMEN	NT				6 6



Report No. : EED32Q80175802 Page 4 of 7

3 General Information

3.1 Client Information

Applicant:	Hisense Visual Technology Co.,Ltd			
Address of Applicant:	No. 218, Qianwangang Road, Economy & Technology Development Zone, Qingdao, China			
Manufacturer:	Hisense Visual Technology Co.,Ltd			
Address of Manufacturer:	No. 218, Qianwangang Road, Economy & Technology Development Zone, Qingdao, China			
Factory:	Shenzhen C&D Electronics Co., Ltd.			
Address of Factory:	9/F Tower 9A, Baoneng Science & Technology Park, 1Qingxiang Road, Longhua District, Shenzhen, Guangdong, China			

3.2 General Description of EUT

Product Name:	/°>	Remote control	C°5	(.)
Model No.:	(6.5)	ERF6B80HL,ERF6**80*******,*stand	ds for 0-9 or A-Z or Blank o	or "(" or ")"
Test model No.:		ERF6B80HL		
Trade Mark:		Hisense		

3.3 Product Specification subjective to this standard

Frequency Range:	2402MHz~2480MHz			
Modulation Type:	GFSK			
Test Power Grade:	Default			
Test Software of EUT:	N/A			(3)
Antenna Type:	PCB antenna	(6,2)		(6,)
Antenna Gain:	-1.33dBi			
Power Supply:	Battery DC 3.0V			
Sample Received Date:	Feb. 28, 2024			
Sample tested Date:	Feb. 28, 2024 to Mar. 19, 2024		(0,)	

Remark:

Company Name and Address shown on Report, the sample(s) and sample Information was/ were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified.

Model No.: ERF6B80HL,ERF6**80********,*stands for 0-9 or A-Z or Blank or "(" or ")"

Only the model ERF6B80HL was tested, they have same electrical, PCB and layout, only the model names and appearance color are different for marketing requirements.







3.4 Test Location

All tests were performed at:

Centre Testing International Group Co., Ltd

Building C, Hongwei Industrial Park Block 70, Bao'an District, Shenzhen, China

Telephone: +86 (0) 755 33683668 Fax:+86 (0) 755 33683385

No tests were sub-contracted. FCC Designation No.: CN1164

3.5 Deviation from Standards

None.

3.6 Abnormalities from Standard Conditions

3.7 Other Information Requested by the Customer





Report No.: EED32Q80175802 Page 6 of 7

4 SAR Evaluation

4.1 RF Exposure Compliance Requirement

4.1.1 Limits

The SAR-based exemption formula of § 1.1307(b)(3)(i)(B), repeated here as Formula (B.2), applies for single fixed, mobile, and portable RF sources with available maximum time-averaged power or effective radiated power (ERP), whichever is greater, of less than or equal to the threshold Pth (mW).

This method shall only be used at separation distances from 0.5 cm to 40 cm and at frequencies from 0.3 GHz to 6 GHz (inclusive). Pth is given by Formula

$$P_{\text{th}} \text{ (mW)} = \begin{cases} ERP_{20 \text{ cm}} (d/20 \text{ cm})^x & d \le 20 \text{ cm} \\ ERP_{20 \text{ cm}} & 20 \text{ cm} < d \le 40 \text{ cm} \end{cases}$$

where

$$x = -\log_{10}\left(\frac{60}{ERP_{20\,\mathrm{cm}}\sqrt{f}}\right)$$

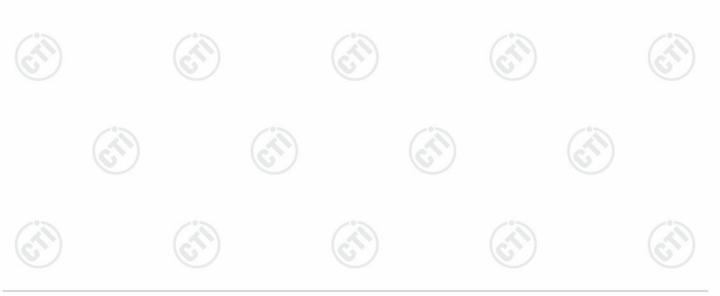
and f is in GHz, d is the separation distance (cm), and ERP20cm is per Formula (B.1).

$$P_{\text{th}} (\text{mW}) = ERP_{20 \text{ cm}} (\text{mW}) = \begin{cases} 2040f & 0.3 \text{ GHz} \le f < 1.5 \text{ GHz} \\ \\ 3060 & 1.5 \text{ GHz} \le f \le 6 \text{ GHz} \end{cases}$$
(B. 1)

The 1 mW Blanket Exemption of § 1.1307(b)(3)(i)(A) applies for single fixed, mobile, and portable RF sources with available maximum time-averaged power of no more than 1 mW, regardless of separation distance.

4.1.2 Test Procedure

Software provided by client enabled the EUT to transmit and receive data at lowest, middle and highest channel individually.





Report No.: EED32Q80175802 Page 7 of 7

4.1.3 EUT RF Exposure Evaluation

For Stand alone:

For Bluetooth LE:

1	Frequency	Max. Conducted	Antenna	EIRP	ERP	ERP	Limit	Result
3	(MHz)	Output power	Gain	(dBm)	(dBm)	(mW)	(mW)	(6)
-		(dBm)	(dBi)					
	2402	1.96	-1.33	0.63	-1.52	0.705	2.788	PASS

Note:

- ①EIRP=conducted power+antenna gain;
- ②ERP=EIRP-2.15;
- ③EIRP(dBm) = Field strength of the fundamental signal(dBuV/m@3m) 95.23;
- $4ERP(mW) = 10^{(ERP (dBm)/10)};$
- ⑤The estimation distance is 0.5cm;
- ©The test data please refer to the report of EED32Q80175801 and only the worst case data was recorded in the report.

The test report is effective only with both signature and specialized stamp, The result(s) shown in this report refer only to the sample(s) tested. Without written approval of CTI, this report can't be reproduced except in full.

*** End of Report **

